

<b>Notice of References Cited</b>	Application/Control No. 10/623,286	Applicant(s)/Patent Under Reexamination FINN ET AL.	
	Examiner Devona E. Faulk	Art Unit 2615	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,674,865	01-2004	Venkatesh et al.	381/107
*	B	US-2004/0158460	08-2004	Finn et al.	704/205
*	C	US-6,252,969	06-2001	Ando, Shigeo	381/103
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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